PCN Number: 202		202	0230112000.1				N Date:	January 12, 2023		
Title: Qualification of new and Datasheet updates				b site (RFAB) using o for select devices	ualified Pro	cess	Technol	ogy, Die Revision		
Cus	tomer	Contact:	Ī	PCN N	<u>lanager</u>	Dept:			Quality Services	
Proposed 1 st Ship Date: A			Anr I / /II / /		Sample requests accepted until:		F C	Feb 12, 2023*		
*Sa	mple r	equests rece	ived	afte	r February 12, 202	23 will not	be supported.			
Change Type:										
Assembly Site				Assembly Process			Assembly Materials			
☑ Design			Electrical Specification			Mechanical Specification				
☐ Test Site			Packing/Shipping/Labeling			Test Process				
☐ Wafer Bump Site			Wafer Bump Material			Wafer Bump Process				
			Wafer Fab Materials			Wafer F	ab Process			
					☐ Part number change					
PCN Details										

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC7) for the device listed below in the product affected section.

C	urrent Fab Site		Additional Fab Site			
Current Fab Site			Additional Fab Site	Process	Wafer Diameter	
DL-LIN	LBC3S	150 mm	RFAB	LBC7	300 mm	
DL-LIN	LBC3S	200 mm	KFAD	LDC/	300 11111	

The die was also changed as a result of the process change.

The datasheet will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The link to the revised datasheets are available in the table below.



MAX3222E

SLLS708C - JANUARY 2006 - REVISED JANUARY 2023

Changes from Revision B (August 2021) to Revision C (January 2023)

Page

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet
MAX3222E	SLLS708B	SLLS708C	http://www.ti.com/product/MAX3222E

Tube, temperature, and ESD protection variants of the devices are included in EOL notice PDN# 20230112003.3.

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-milimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Fab Site Information:

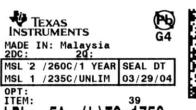
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DL-LIN	DLN	USA	Dallas
RFAB	RFB	USA	Richardson

Die Rev:

Current New

Die Rev [2P]	Die Rev [2P]
G	В

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(2P) REV: (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

MAX3222EIDBR

For alternate parts with similar or improved performance, please visit the product page on $\overline{\text{TI.com}}$

Qualification Report Approve Date 21-DECEMBER -2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: PTRS3222EIDBR	QBS Reference: TPS51217DSCR	QBS Reference: SRC4190IDB	QBS Reference: TRSF3222EIPWR	QBS Reference: TPD3S714QDBQRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	3/231/0	-	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	3/231/0	-	-
HTOL	B1	Life Test	135C	635 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	408 Hours	-	-	-	-	3/231/0
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	-	-	-	3/2400/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	1/76/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	1/76/0	3/228/0
SD	C3	PB Solderability	Post 8hr steam	-	-	-	-	-	3/45/0
SD	C3	PB-Free Solderability	Post 8hr steam	-	-	-	-	-	3/45/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	3/30/0
ESD	E2	ESD CDM	-	1500 Volts	-	3/9/0	-	-	3/9/0

ESD	E2	ESD CDM	-	2000 Volts	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-
ESD	E2	ESD HBM	-	16000 Volts	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	2000 Volts	-	3/9/0	-	-	-
ESD	E2	ESD HBM	-	4000 Volts	-	-	-	1/3/0	3/9/0
LU	E4	Latch-Up	Per JESD78	-	-	3/18/0	-	1/3/0	3/18/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/5/0	3/60/0	-	1/5/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	3/90/0

- · QBS: Qual By Similarity
- Qual Device PTRS3222EIDBR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail				
WW Change Management Team	PCN ww admin team@list.ti.com				

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disdaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.